## Notice of References Cited Application/Control No. 10/789,985 Examiner Patrick H. Mackey Applicant(s)/Patent Under Reexamination HAYASHI ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2004/0175217	09-2004	Nakamura et al.	399/407
	В	US-5,112,034	05-1992	Uto et al.	270/58.12
	С	US-5,765,824	06-1998	Kawano et al.	270/58.11
•	D	US-6,332,606	12-2001	Seki, Nobuyoshi	270/59
	E	US-6,315,288	11-2001	Sugishima et al.	271/303
	F	US-5,289,251	02-1994	Mandel et al.	399/407
	G	US-			
	Н	US-			
	ı	US-		·	
	J	US-			
	К	US-		·	
	L	US-		·	
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 05286619 A	11-1993	Japan	NAKAZATO et al.	B65H 29/20
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.